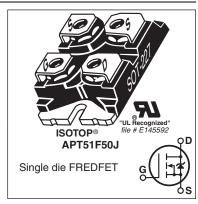




500V, 51A, 0.075Ω Max, $t_{rr} \le 310ns$

N-Channel FREDFET

Power MOS 8^{TM} is a high speed, high voltage N-channel switch-mode power MOSFET. This 'FREDFET' version has a drain-source (body) diode that has been optimized for high reliability in ZVS phase shifted bridge and other circuits through reduced t_{rr} , soft recovery, and high recovery dv/dt capability. Low gate charge, high gain, and a greatly reduced ratio of $C_{\text{rss}}/C_{\text{iss}}$ result in excellent noise immunity and low switching loss. The intrinsic gate resistance and capacitance of the poly-silicon gate structure help control di/dt during switching, resulting in low EMI and reliable paralleling, even when switching at very high frequency.



FEATURES

- · Fast switching with low EMI
- · Low trr for high reliability
- Ultra low C_{rss} for improved noise immunity
- · Low gate charge
- · Avalanche energy rated
- RoHS compliant

TYPICAL APPLICATIONS

- · ZVS phase shifted and other full bridge
- Half bridge
- PFC and other boost converter
- Buck converter
- · Single and two switch forward
- Flyback

Absolute Maximum Ratings

Symbol	Parameter	Ratings	Unit
L	Continuous Drain Current @ T _C = 25°C	51	
'D	Continuous Drain Current @ T _C = 100°C	32	Α
I _{DM}	Pulsed Drain Current ^①	230	
V _{GS}	Gate-Source Voltage	±30	V
E _{AS}	Single Pulse Avalanche Energy®	1580	mJ
I _{AR}	Avalanche Current, Repetitive or Non-Repetitive	37	Α

Thermal and Mechanical Characteristics

Symbol	Characteristic	Min	Тур	Max	Unit	
P _D	Total Power Dissipation @ T _C = 25°C			480	W	
$R_{\theta JC}$	Junction to Case Thermal Resistance			0.26	0.26 °C/W	
$R_{\theta CS}$	Case to Sink Thermal Resistance, Flat, Greased Surface		0.15			
T _J ,T _{STG}	Operating and Storage Junction Temperature Range	-55		150	°C	
V _{Isolation}	RMS Voltage (50-60hHz Sinusoidal Waveform from Terminals to Mounting Base for 1 Min.)	2500			V	
W _T	Package Weight		1.03		OZ	
			29.2		g	
Torque	Terminals and Mounting Screws.			10	in∙lbf	
				1.1	N⋅m	

Symbol	Parameter	Test Conditions		Min	Тур	Max	Unit
V _{BR(DSS)}	Drain-Source Breakdown Voltage	$V_{GS} = 0V, I_{D} = 250\mu A$		500			V
$\Delta V_{BR(DSS)}/\Delta T_{J}$	Breakdown Voltage Temperature Coefficient	Reference to 25°C, I _D = 250µA			0.60		V/°C
R _{DS(on)}	Drain-Source On Resistance®	V _{GS} = 10V, I _D = 37A			0.064	0.075	Ω
V _{GS(th)}	Gate-Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 2.5 \text{mA}$		2.5	4	5	V
$\Delta V_{GS(th)}/\Delta T_{J}$	Threshold Voltage Temperature Coefficient				-10		mV/°C
	Zero Gate Voltage Drain Current	V _{DS} = 500V T	= 25°C			250	μA
DSS		V _{GS} = 0V T	_J = 125°C			1000	μΑ
I _{GSS}	Gate-Source Leakage Current	V _{GS} = ±30V				±100	nA

Dynamic Characteristics

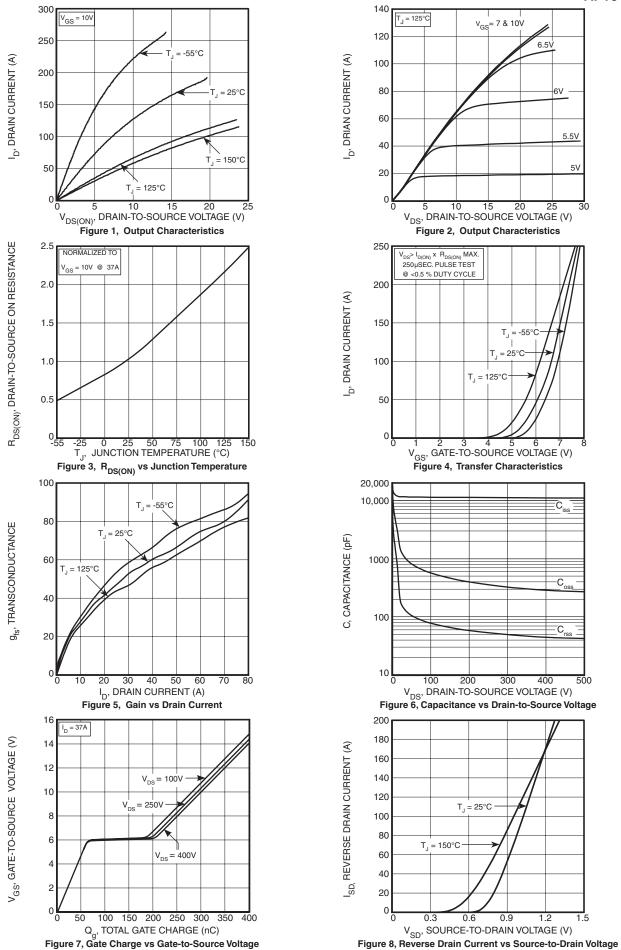
T₁ = 25°C unless otherwise specified

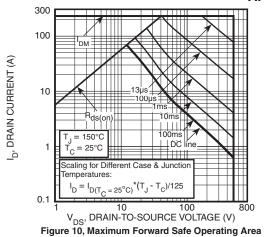
Symbol	Parameter	Test Conditions	Max	Unit	
9 _{fs}	Forward Transconductance	$V_{DS} = 50V, I_{D} = 37A$	55		S
C _{iss}	Input Capacitance	V 0V V 05V	11600		
C _{rss}	Reverse Transfer Capacitance	$V_{GS} = 0V, V_{DS} = 25V$ f = 1MHz	160		
C _{oss}	Output Capacitance	7 - 111112	1250		
$C_{o(cr)} \textcircled{4}$	Effective Output Capacitance, Charge Related	V 0V V 0V+0 222V	725		pF
C _{o(er)} ⑤	Effective Output Capacitance, Energy Related	$V_{GS} = 0V, V_{DS} = 0V \text{ to } 333V$	365		
Q _g	Total Gate Charge	V 01 10V 1 07A	290		
Q_{gs}	Gate-Source Charge	$V_{GS} = 0 \text{ to } 10V, I_{D} = 37A,$ $V_{DS} = 250V$	65		nC
Q_{gd}	Gate-Drain Charge	V _{DS} = 250V	130		
t _{d(on)}	Turn-On Delay Time	Resistive Switching	45		
t _r	Current Rise Time	V _{DD} = 333V, I _D = 37A	55		ns
t _{d(off)}	Turn-Off Delay Time	$R_{G}^{} = 2.2\Omega^{\textcircled{6}}, V_{GG}^{} = 15V$	120		115
t _f	Current Fall Time		39		

Source-Drain Diode Characteristics

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
Is	Continuous Source Current (Body Diode)	MOSFET symbol showing the	\$		51	A
I _{SM}	Pulsed Source Current (Body Diode) ^①	integral reverse p-n unction diode (body diode)	7		230	^
V _{SD}	Diode Forward Voltage	$I_{SD} = 37A, T_{J} = 25^{\circ}C, V_{GS} = 0V$			1.0	V
t _{rr}	Deverse Bessyant Time	T _J = 25°C			310	no
rr	Reverse Recovery Time	T _J = 125°C			570	ns
Q _{rr}	Reverse Recovery Charge	$I_{SD} = 37A^{\textcircled{3}}$ $T_{J} = 25^{\circ}C$		1.48		
Grr		$V_{DD} = 100V$ $T_{J} = 125^{\circ}C$		3.85		μC
	Reverse Recovery Current	$di_{SD}/dt = 100A/\mu s$ $T_J = 25^{\circ}C$		11.3		Α
'rrm		T _J = 125°C		16.6] ^
dv/dt	Peak Recovery dv/dt	$I_{SD} \le 37A$, di/dt $\le 1000A/\mu s$, $V_{DD} = 333V$ $T_J = 125^{\circ}C$	/,		20	V/ns

- (1) Repetitive Rating: Pulse width and case temperature limited by maximum junction temperature.
- ② Starting at $T_J = 25^{\circ}C$, L = 2.31 mH, $R_G = 25\Omega$, $I_{AS} = 37A$.
- ③ Pulse test: Pulse Width < 380μs, duty cycle < 2%.
- (4) $C_{o(cr)}$ is defined as a fixed capacitance with the same stored charge as C_{OSS} with $V_{DS} = 67\%$ of $V_{(BR)DSS}$. (5) $C_{o(er)}$ is defined as a fixed capacitance with the same stored energy as C_{OSS} with $V_{DS} = 67\%$ of $V_{(BR)DSS}$. To calculate $C_{o(er)}$ for any value of V_{DS} less than $V_{(BR)DSS}$, use this equation: $C_{o(er)} = -1.65E-7/V_{DS}^2 + 5.51E-8/V_{DS} + 2.03E-10$.
- ⑥ R_G is external gate resistance, not including internal gate resistance or gate driver impedance. (MIC4452)





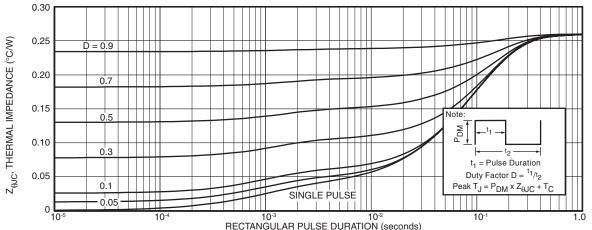


Figure 11. Maximum Effective Transient Thermal Impedance Junction-to-Case vs Pulse Duration

SOT-227 (ISOTOP®) Package Outline

